

Silicon N-Channel Power MOSFET

Description

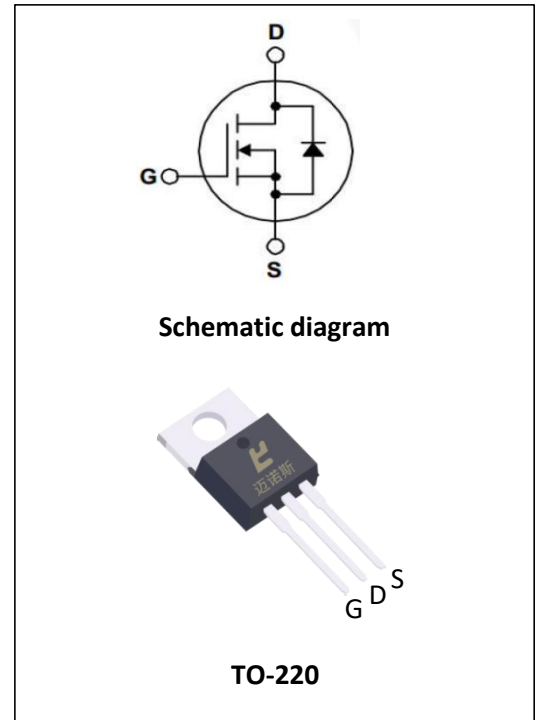
The IRLZ44NPBF uses advanced trench technology and design to provide Excellent  $R_{DS(ON)}$ . It can be used in a wide variety of applications.

General Features

- ①  $V_{DS}=60V, I_D=50A$   
 $R_{dson} \leq 18m\Omega @ V_{GS}=10V$  (Typ:15.0 m $\Omega$ )
- ② Low ON Resistance
- ③ Low Reverse transfer capacitances
- ④ 100% Single Pulse avalanche energy Test

Application

- ① Power switching application
- ② Load switch



Package Marking And Ordering Information

Ordering Codes	Package	Product Code	Packing
IRLZ44NPBF	TO-220	IRLZ44NPBF	Tube

ABSOLUTE RATINGS (at  $T_c=25^\circ C$  unless otherwise specified)

Symbol	Parameter	Value	Units
$V_{DSS}$	Drain-to-Source Breakdown Voltage	60	V
$I_D$	Drain Current (continuous) at $T_c=25^\circ C$	50	A
$I_{DM}$	Drain Current (pulsed)	200	A
$V_{GS}$	Gate to Source Voltage	+/-20	V
$P_{tot}$	Total Dissipation at $T_c=25^\circ C$	100	W
$T_j$	Max. Operating Junction Temperature	175	$^\circ C$
$E_{as}$	Single Pulse Avalanche Energy	256	mj

Thermal characteristics

Symbol	Parameter	Typ	Units
$R_{\theta JC}$	Junction-to-Case	1.3	$^\circ C/W$

**Electrical Characteristics (at  $T_c=25^\circ\text{C}$  unless otherwise specified)**

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
$V_{DS}$	Drain-source Voltage	$V_{GS}=0V, I_D=250\mu A$	60	--	--	V
$R_{DS(on)}$	Static Drain-to-Source on-Resistance	$V_{GS}=10V, I_D=25A$	--	15	18	m $\Omega$
$V_{GS(th)}$	Gated Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	1.0	1.9	2.5	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=60V, V_{GS}=0V$	--	--	1.0	$\mu A$
$I_{GSS(F)}$	Gated Body Leakage Current	$V_{GS}=+20V,$	--	--	100	nA
$I_{GSS(R)}$	Gated Body Leakage Current	$V_{GS}=-20V,$	--	--	-100	nA
$C_{iss}$	Input Capacitance	$V_{GS}=0V,$ $V_{DS}=25V,$ $f=1.0\text{MHZ}$	--	2200	--	pF
$C_{oss}$	Output Capacitance		--	225	--	pF
$C_{rss}$	Reverse Transfer Capacitance		--	165	--	pF
$Q_g$	Total Gate Charge	$V_{DS}=25V$ $I_D=10A$ $V_{GS}=10V$	--	58	--	nC
$Q_{gs}$	Gate-Source Charge		--	6	--	nC
$Q_{gd}$	Gate-Drain Charge		--	15	--	nC

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
$t_{d(on)}$	Turn-on Delay Time	$V_{DD}=25V, I_D=10A, R_L=0.3\Omega$ $V_{GS}=10V, R_G=6.8\Omega$	--	20	--	nS
$t_r$	Turn-on Rise Time		--	90	--	nS
$t_{d(off)}$	Turn-off Delay Time		--	45	--	nS
$t_f$	Turn-off Fall Time		--	90	--	nS

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
$I_{SD}$	S-D Current(Body Diode)		--	50	--	A
$I_{SDM}$	Pulsed S-D Current(Body Diode)		--	200	--	A
$V_{SD}$	Diode Forward Voltage	$V_{GS}=0V, I_{DS}=25A$	--	--	1.4	V
$t_{rr}$	Reverse Recovery Time	$T_j=25^\circ\text{C}, I_F=25A$ $di/dt=100A/\mu s$	--	102	--	nS
$Q_{rr}$	Reverse Recovery Charge		--	50	--	nC
*Pulse Test: Pulse Width $\leq 300\mu s$ , Duty Cycle $\leq 2\%$						

Characteristics Curves

Figure 1. Output Characteristics (T<sub>J</sub>=25°C)

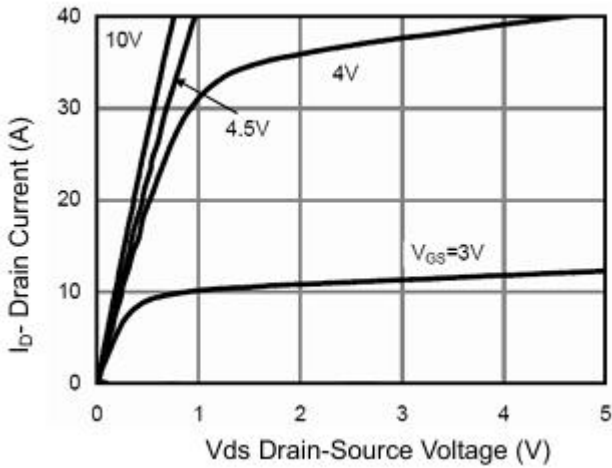


Figure 2. Transfer Characteristics

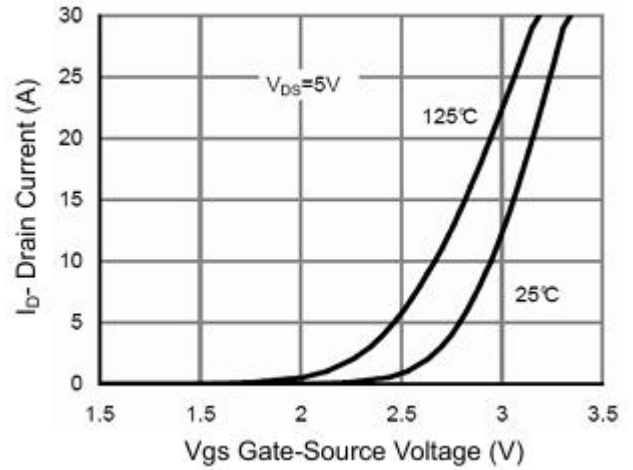


Figure 3. R<sub>DS(on)</sub>-Drain Current

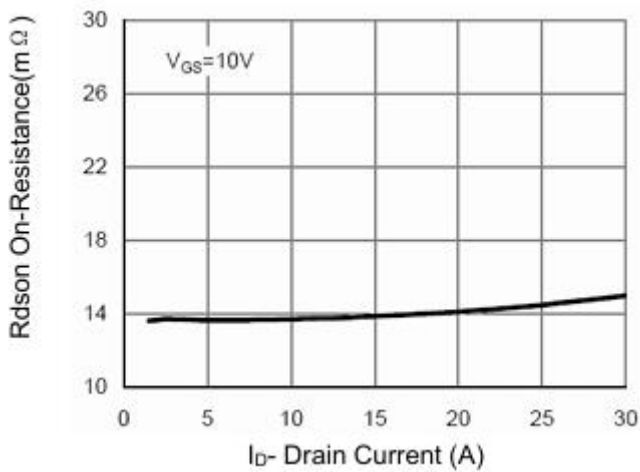


Figure 4. R<sub>DS(on)</sub>-Junction Temperature

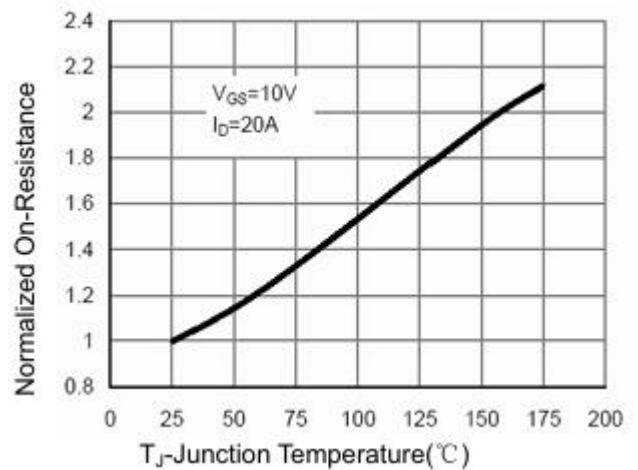


Figure 5. Gate Charge

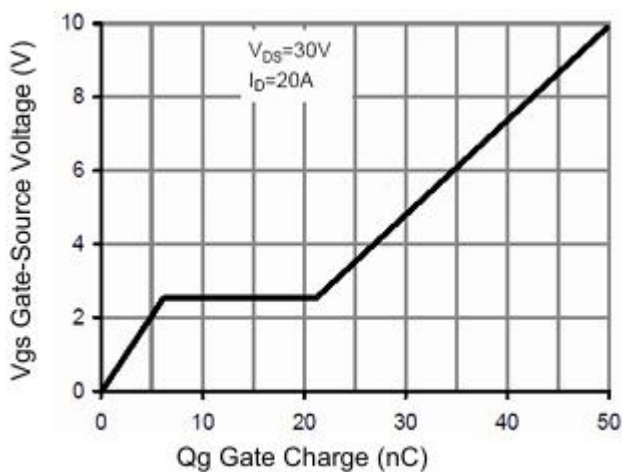


Figure 6. Source- Drain Diode Forward

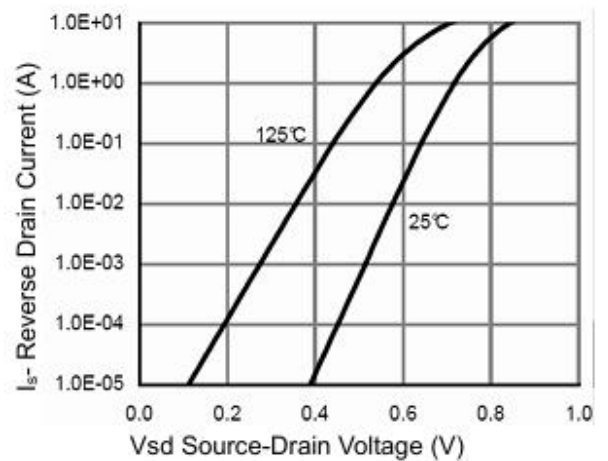


Figure 7. Capacitance vs Vds

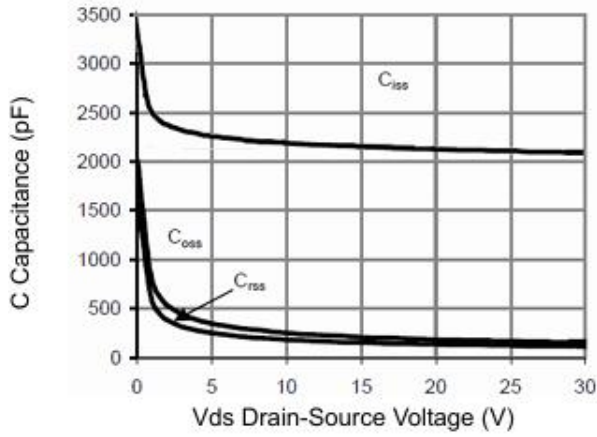


Figure 8. Safe Operation Area

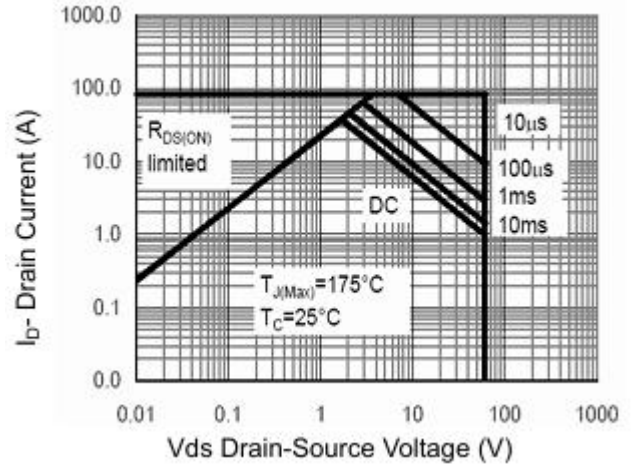


Figure 9. BVDS vs Junction Temperature

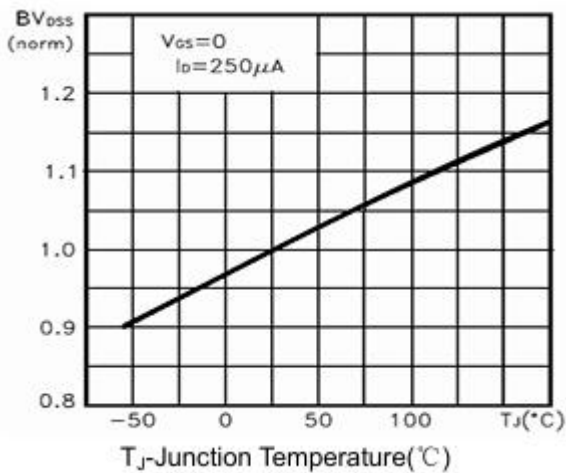


Figure 10. VGS(th) vs Junction Temperature

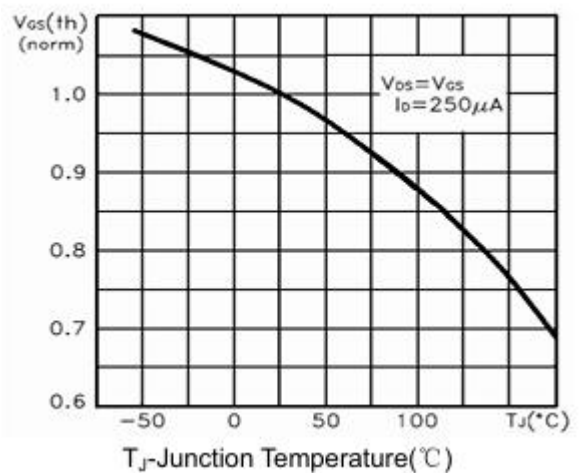
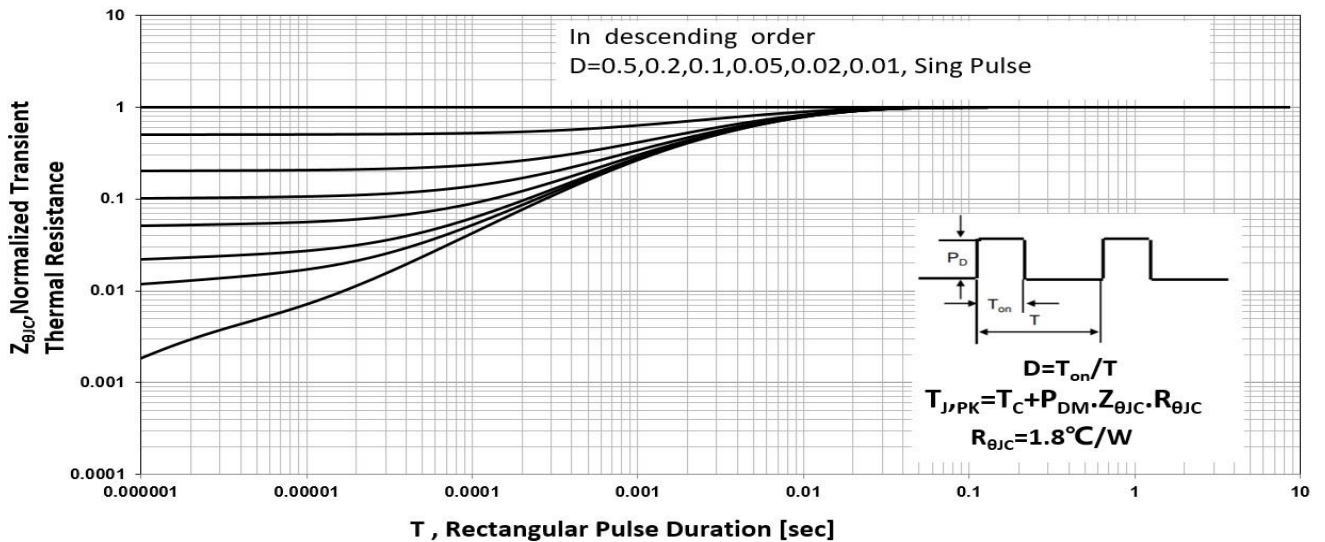
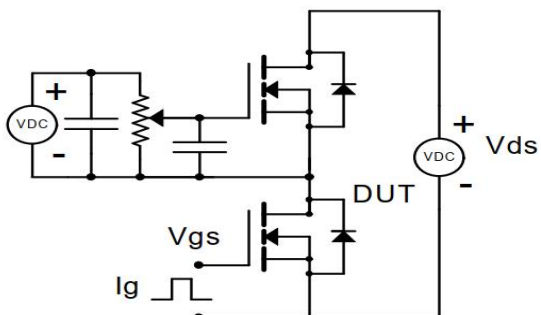
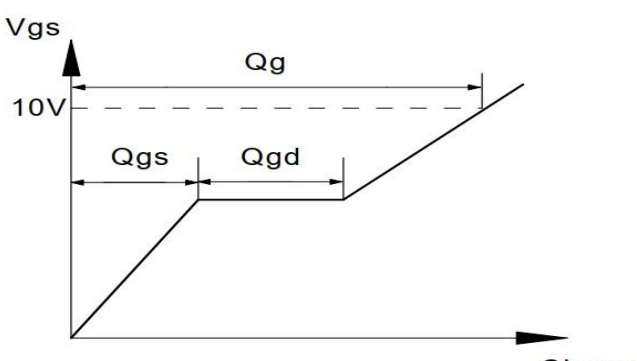
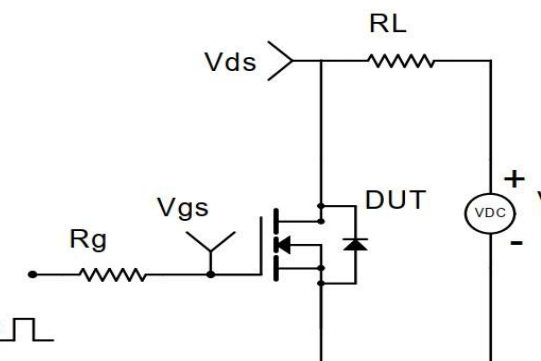
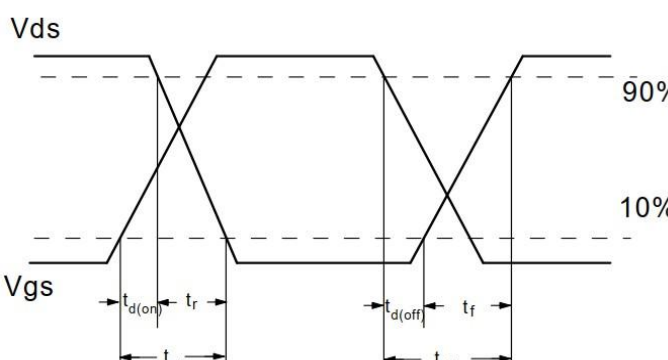
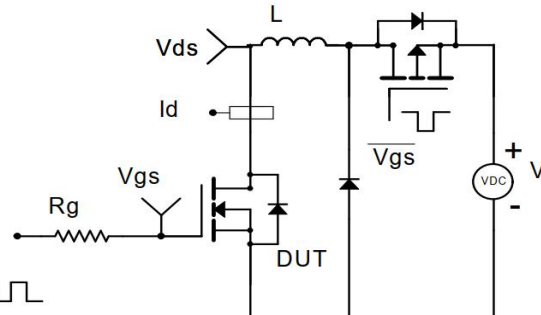
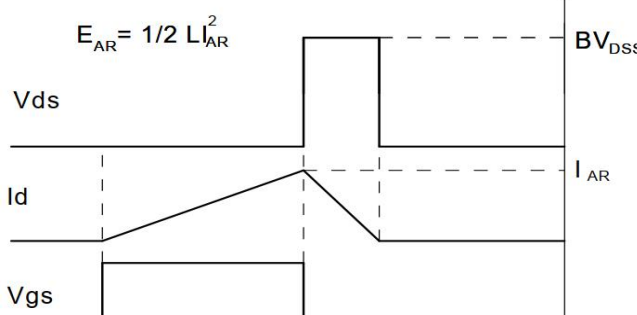
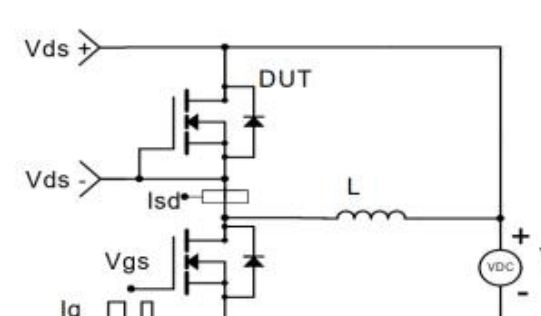
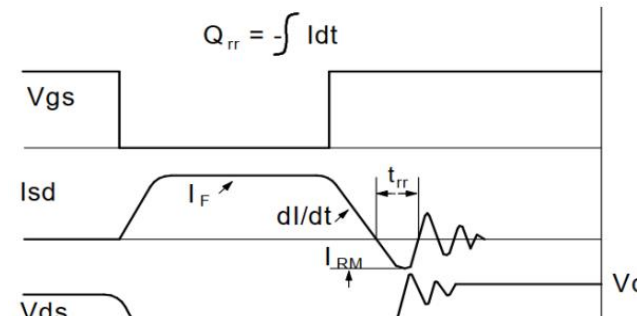


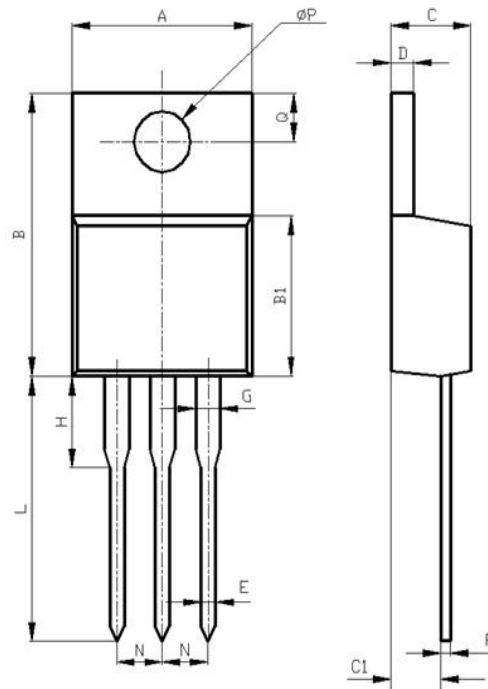
Figure 11 Normalized Maximum Transient Thermal Impedance



Test Circuit and Waveform

<p style="text-align: center;"><b>Gate Charge Test Circuit</b></p> 	<p style="text-align: center;"><b>Gate Charge Test Waveform</b></p> 
<p style="text-align: center;"><b>Resistive Switching Test Circuit</b></p> 	<p style="text-align: center;"><b>Resistive Switching Test Waveforms</b></p> 
<p style="text-align: center;"><b>Unclamped Inductive Switching (UIS) Test Circuit</b></p> 	<p style="text-align: center;"><b>Unclamped Inductive Switching (UIS) Test Waveforms</b></p> 
<p style="text-align: center;"><b>Diode Recovery Test Circuit</b></p> 	<p style="text-align: center;"><b>Diode Recovery Test Waveforms</b></p> 

Package Description



Items	Values(mm)	
	MIN	MAX
A	9.60	10.6
B	15.0	16.0
B1	8.90	9.50
C	4.30	4.80
C1	2.30	3.10
D	1.20	1.40
E	0.70	0.90
F	0.30	0.60
G	1.17	1.37
H	2.70	3.80
L	12.6	14.8
N	2.34	2.74
Q	2.40	3.00
$\phi P$	3.50	3.90

TO-220 package

**NOTE:**

1. Exceeding the maximum ratings of the device in performance may cause damage to the device, even the permanent failure, which may affect the dependability of the machine. Please do not exceed the absolute maximum ratings of the device when circuit designing.
2. When installing the heat sink, please pay attention to the torsional moment and the smoothness of the heat sink.
3. MOSFETs is the device which is sensitive to the static electricity, it is necessary to protect the device from being damaged by the static electricity when using it.
4. Shenzhen Minos reserves the right to make changes in this specification sheet and is subject to change without prior notice.

**CONTACT:**

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